ECE 271 Electronic Circuits I

Topic 8 Complementary MOS (CMOS) Logic Design

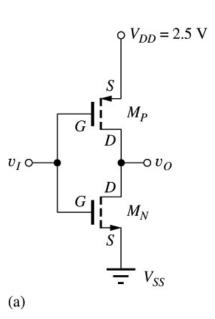
Chapter Goals

- Introduce CMOS logic concepts
- Explore the voltage transfer characteristics of CMOS inverters
- Learn to design basic and complex CMOS logic gates
- Discuss the static and dynamic power in CMOS logic
- Present expressions for dynamic performance of CMOS logic devices
- Present noise margins for CMOS logic
- Introduce design techniques for "cascade buffers"

CMOS Inverter Technology

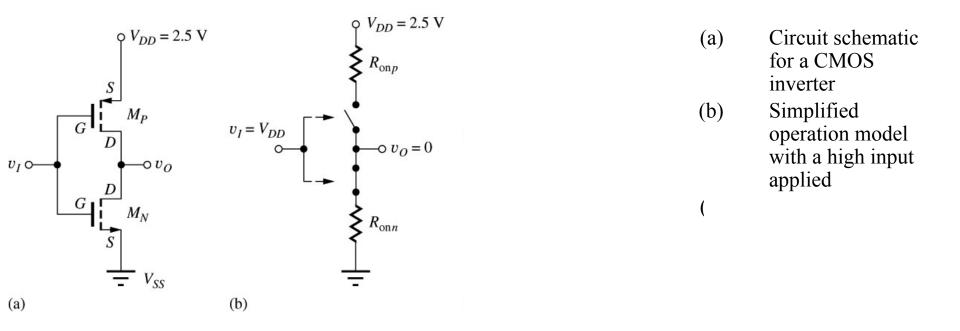
- Complementary MOS, or CMOS, needs both PMOS and NMOS devices for the logic gates to be realized
- The concept of CMOS was introduced in 1963 by Wanlass and Sah.
- CMOS are more complicated in design and production, thus are more expensive to fabricate
- Have not been widely used until the 1980's as NMOS microprocessors started to dissipating as much as 50 W and more and alternative design technique was needed
- CMOS dominate digital IC design today

CMOS Inverter



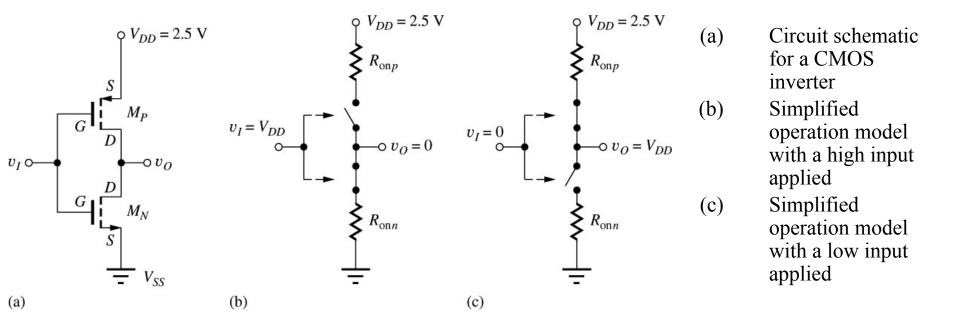
(a) Circuit schematic for a CMOS inverter

CMOS Inverter



• When v_I is pulled high (to V_{DD}), the PMOS transistor is turned off, while the NMOS device is turned on pulling the output down to V_{SS}

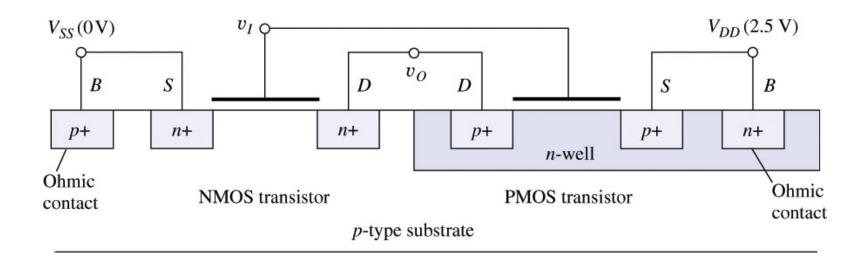
CMOS Inverter

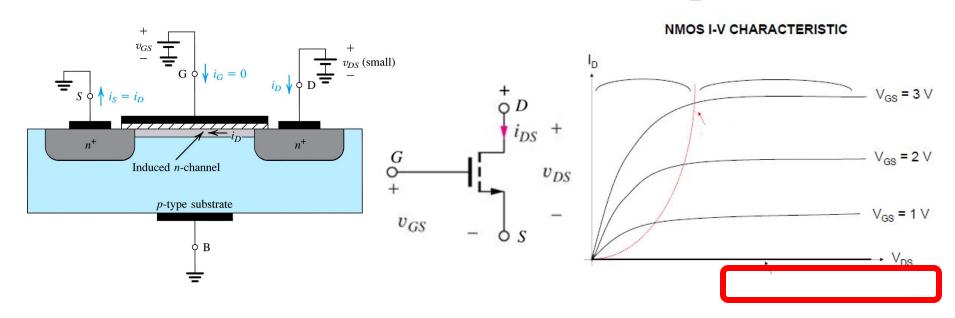


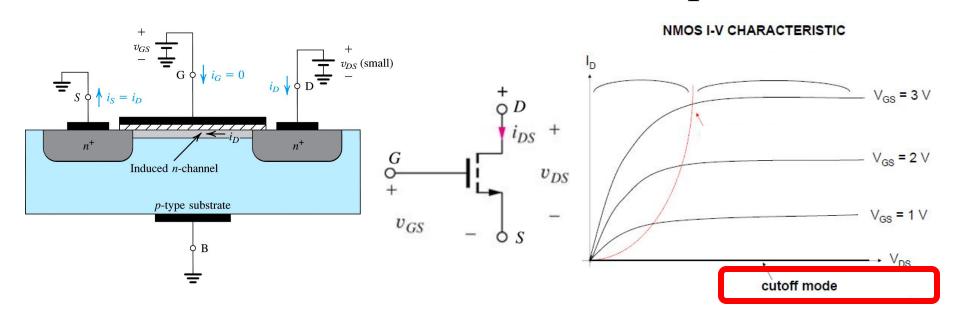
- When v_I is pulled high (to V_{DD}), the PMOS transistor is turned off, while the NMOS device is turned on pulling the output down to V_{SS}
- When v_I is pulled low (to V_{SS}), the NMOS transistor is turned off, while the PMOS device is turned on pulling the output up to V_{DD}

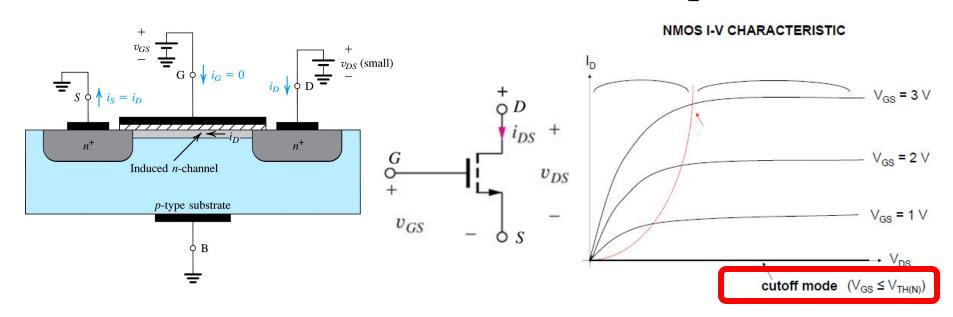
CMOS Inverter Technology

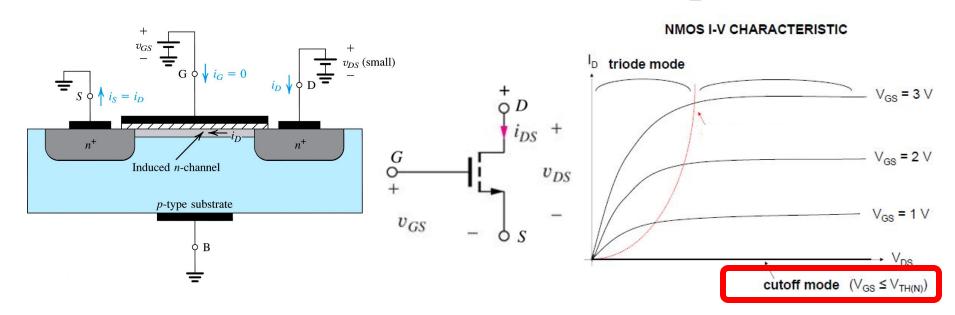
- The CMOS inverter consists of a PMOS device stacked on top on an NMOS device, but they need to be fabricated on the same wafer
- To accomplish this, the technique of "n-well" implantation is needed as shown in this cross-section of a CMOS inverter

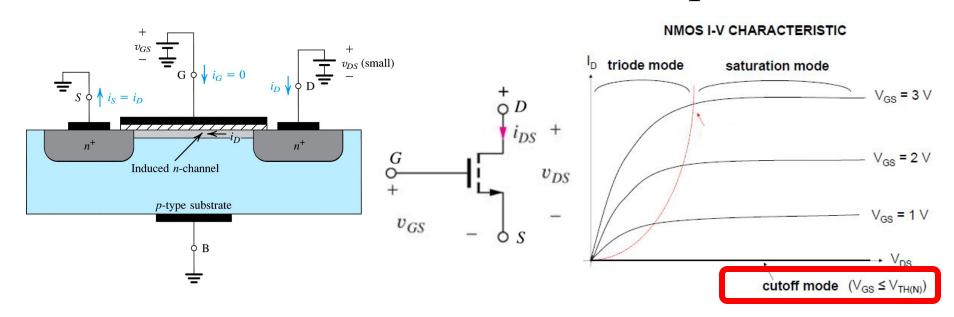


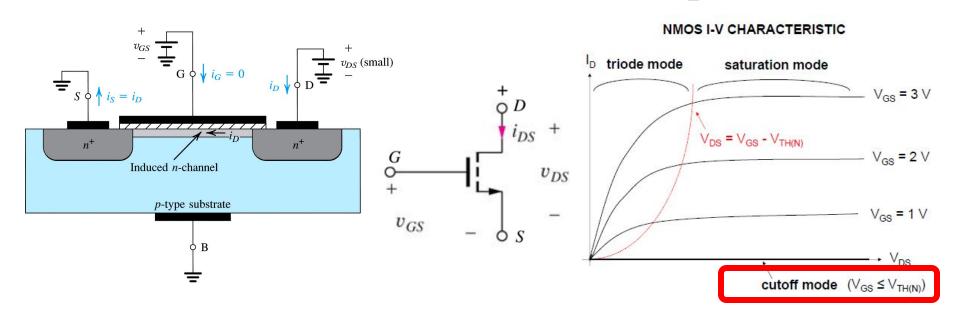


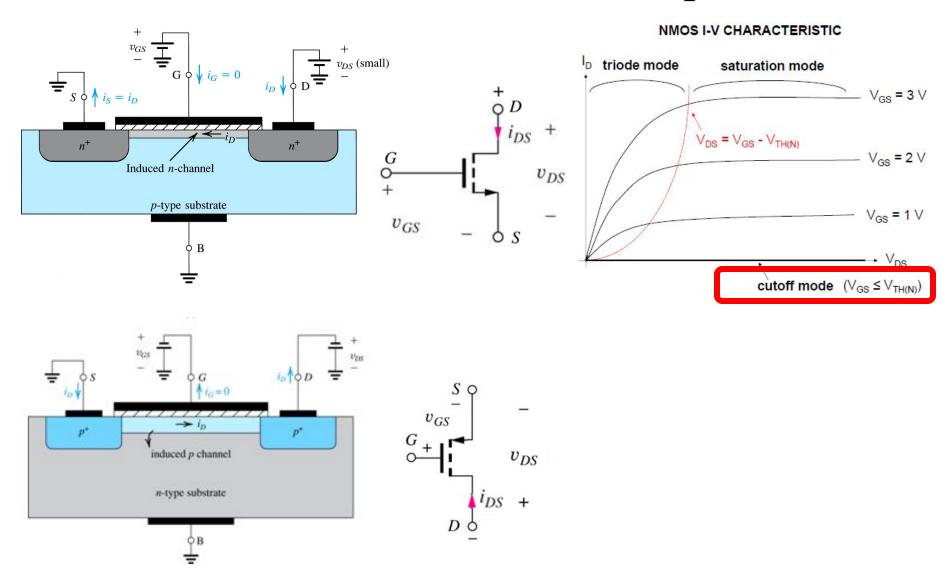


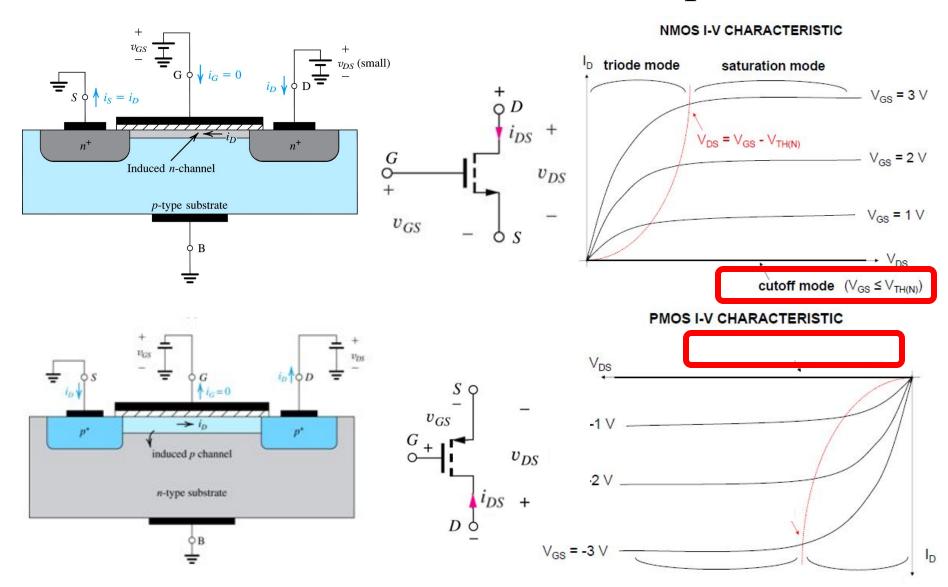


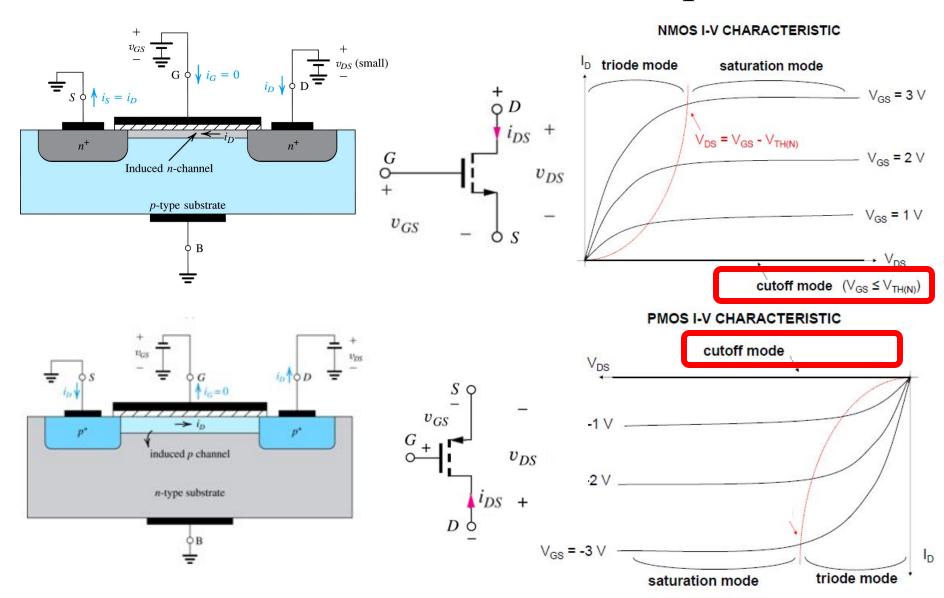


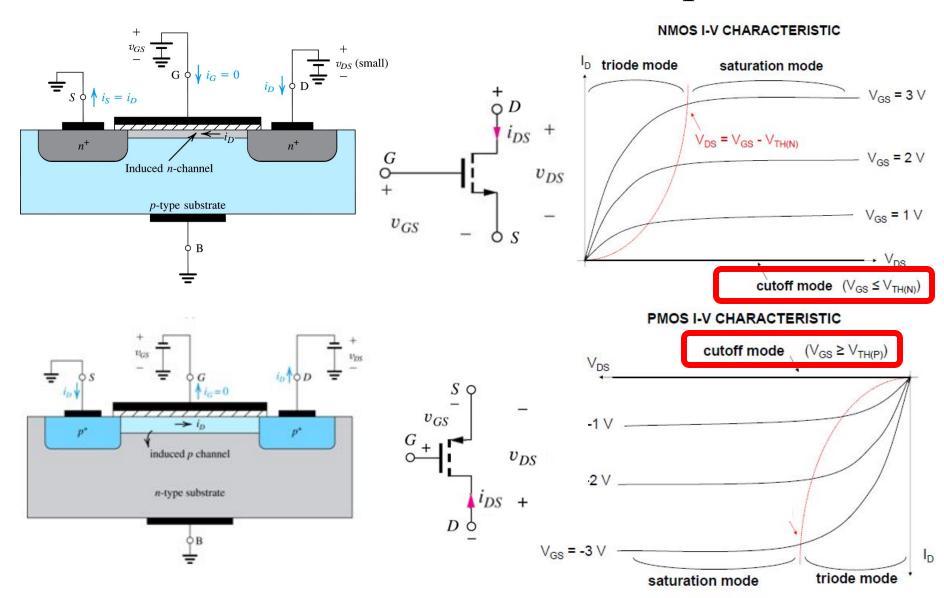


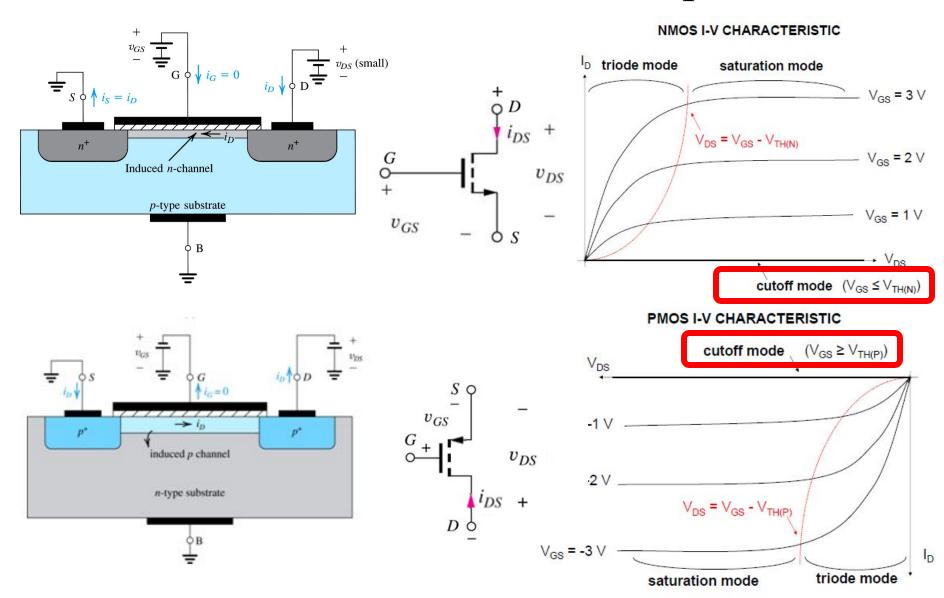


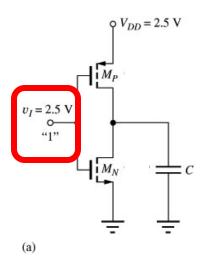


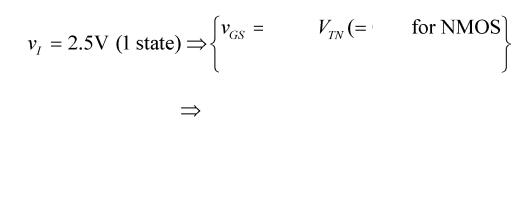


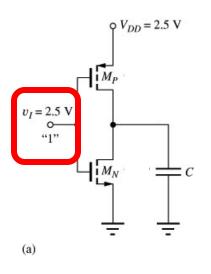




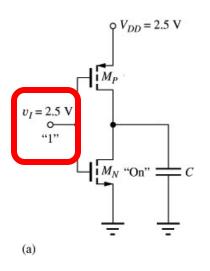






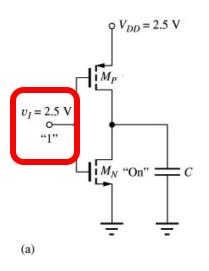


$$v_I = 2.5 \text{V (1 state)} \Rightarrow \begin{cases} v_{GS} = 2.5 > V_{TN} (= 0.6) \text{ for NMOS} \end{cases}$$



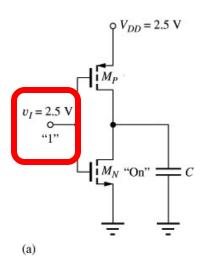
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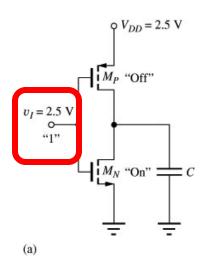
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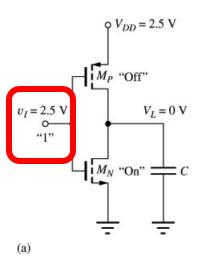
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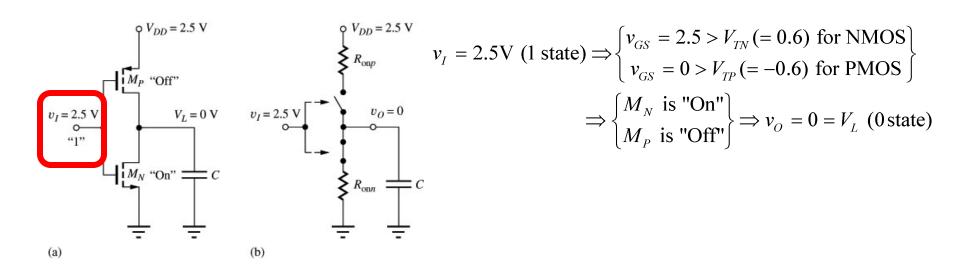


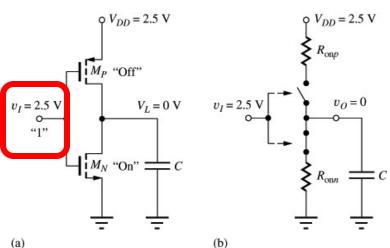
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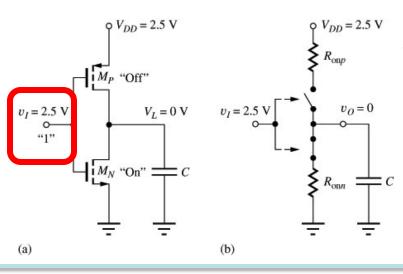
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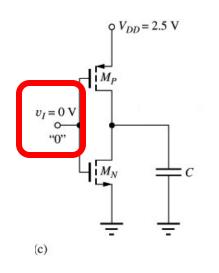
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The capacitor discharges through R_{onN}, current exists only during discharge,
 no dc current exists.

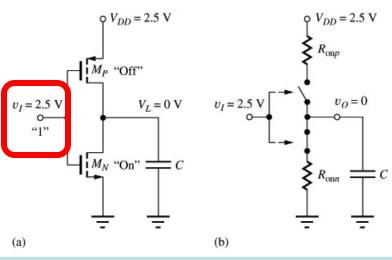


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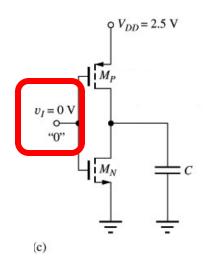


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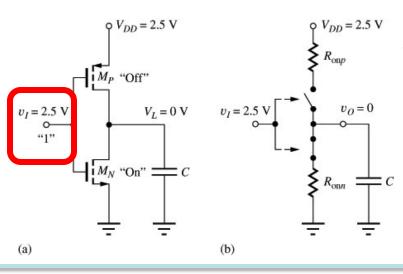


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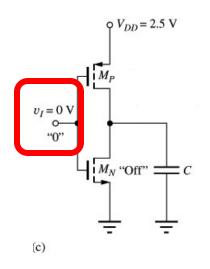


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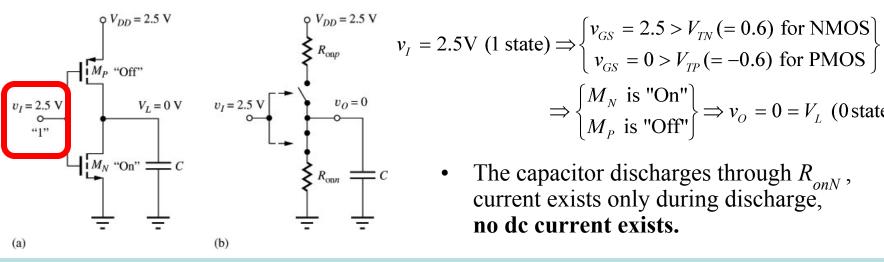
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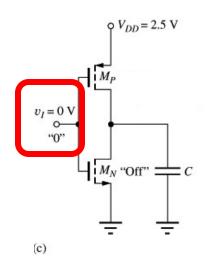


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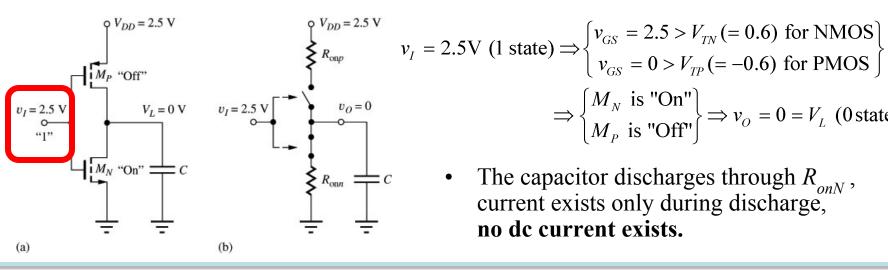


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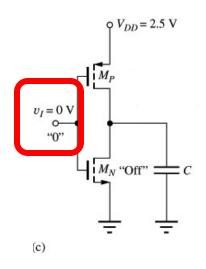


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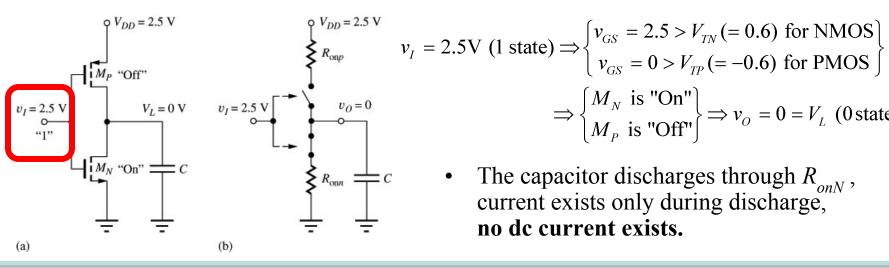


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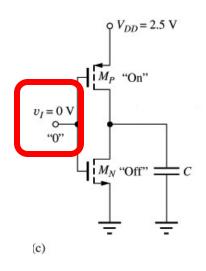


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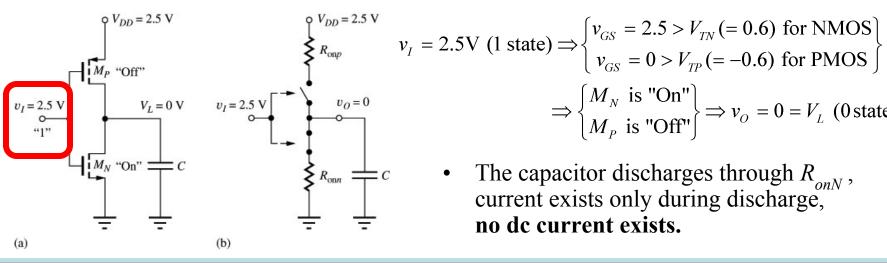


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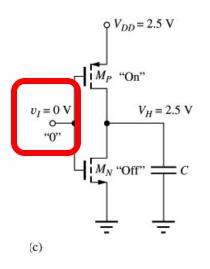


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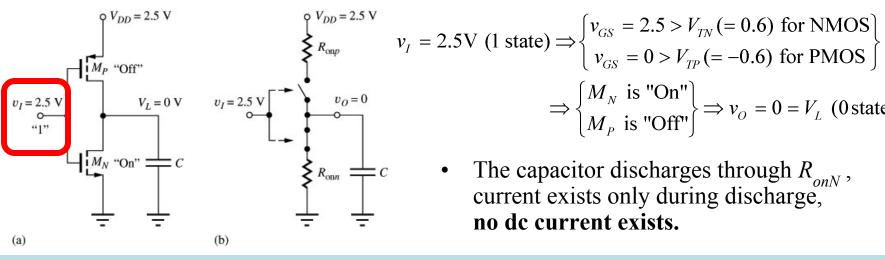
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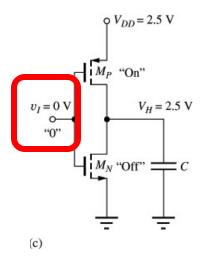
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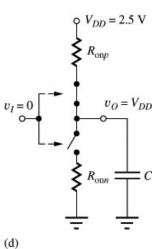


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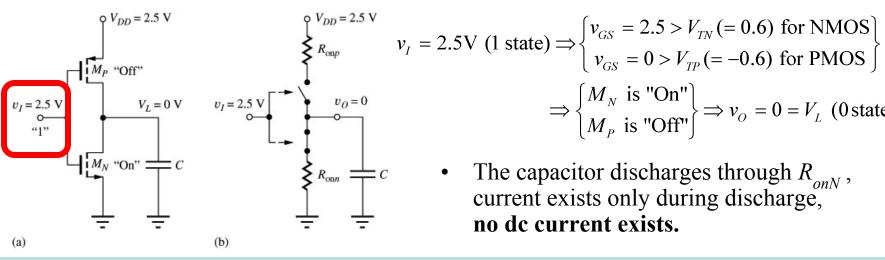


(b)
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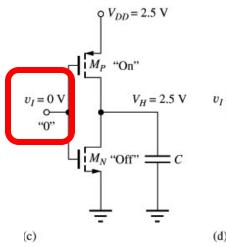
$$V_{Ronp} = 0 \text{ V} \text{ (0 state)} \Rightarrow \begin{cases} v_{GS} = 0 < V_{TN} \text{ (= 0.6) for NMOS} \\ v_{GS} = -2.5 < V_{TP} \text{ (= -0.6) for PMOS} \end{cases}$$

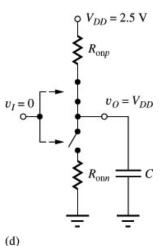
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no dc current exists.





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• The capacitor charges through R_{onP} , current exists only during charging, no dc current exists.

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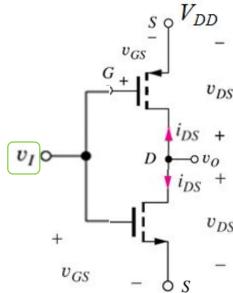
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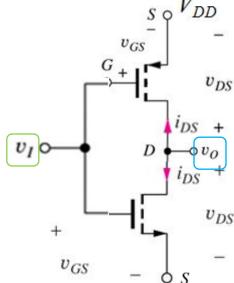
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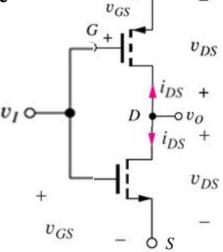
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• We select the input voltage V_p the output voltage V_O , and the NMOS drain current I_{DN} as the variables of choice.

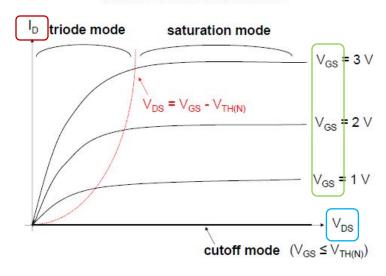
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- We select the input voltage V_P the output voltage V_O , and the NMOS drain current I_{DSN} as the variables of choice.
- The PMOS *I-V* relationship can be transformed as follows:

$$\begin{split} I_{DSp} &= -I_{DSn} \\ V_{GSn} &= V_I; & V_{GSp} &= V_I - V_{DD} \\ V_{DSn} &= V_O; & V_{DSp} &= V_O - V_{DD} \end{split}$$

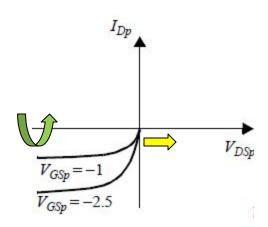


• The *I-V* curves for NMOS are already plotted in the selected coordinate set V_{in} , V_{out} and I_{DN} , so no change is needed.

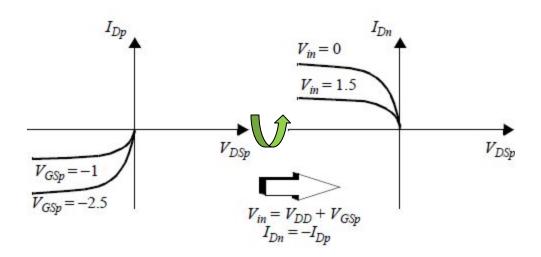
NMOS I-V CHARACTERISTIC



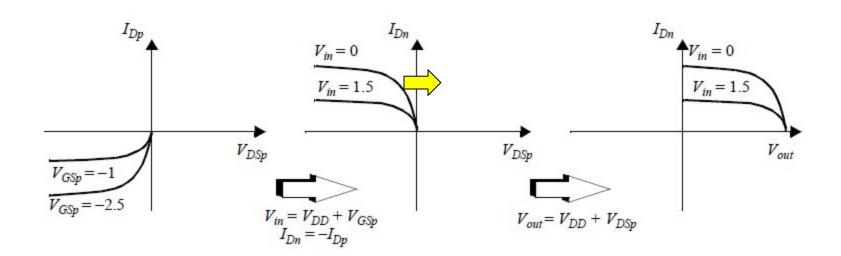
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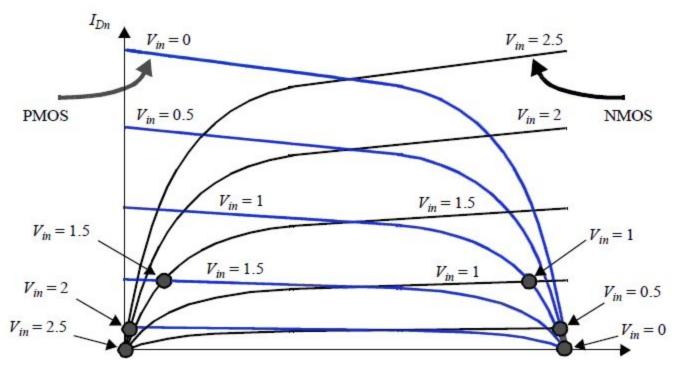
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- This procedure is outlined below, where the subsequent steps to adjust the original PMOS I-V curves to the common coordinate set V_{in} , V_{out} and I_{Dn} are illustrated (in this example $V_{DD} = 2.5 \text{V}$.



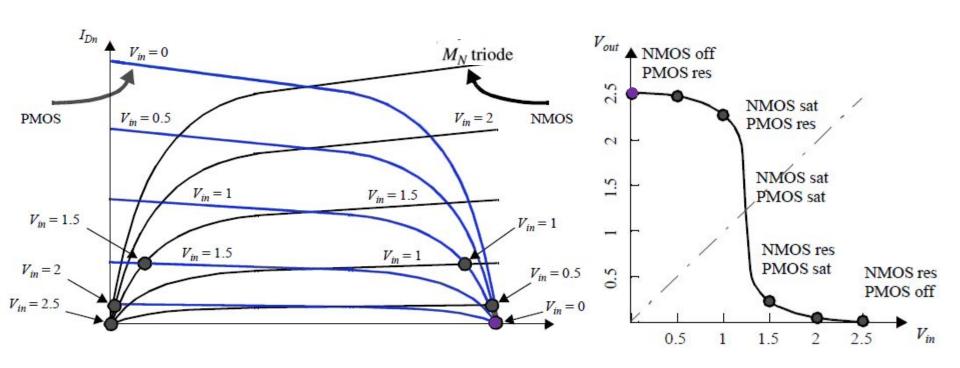
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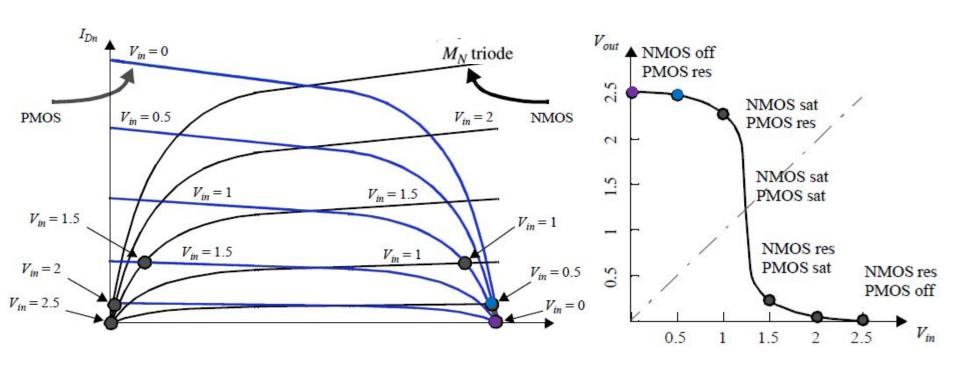
- Now we can superimpose the load curves of the PMOS on the *IV* curves of the NMOS.
- For a dc operating points to be valid, the currents through the NMOS and PMOS devices must be equal. Graphically, this means that the dc points must be located at the intersection of corresponding load lines.
- Some of those points (for Vin = 0, 0.5, 1, 1.5, 2, and 2.5 V) are marked on the graph.



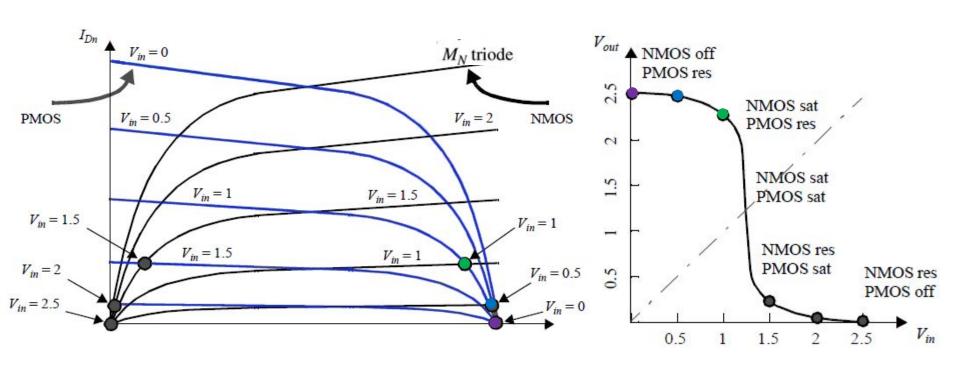
- All operating points are located either at the high or low output levels.
- The VTC of the inverter hence exhibits a very narrow transition zone.
- This results from the high gain during the switching transient, when both NMOS and PMOS are simultaneously on, and in saturation.
- In that operation region, a small change in the input voltage results in a large output variation.



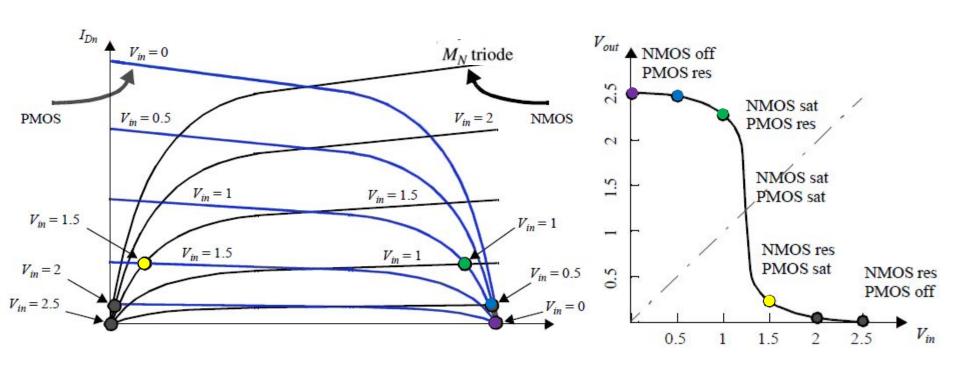
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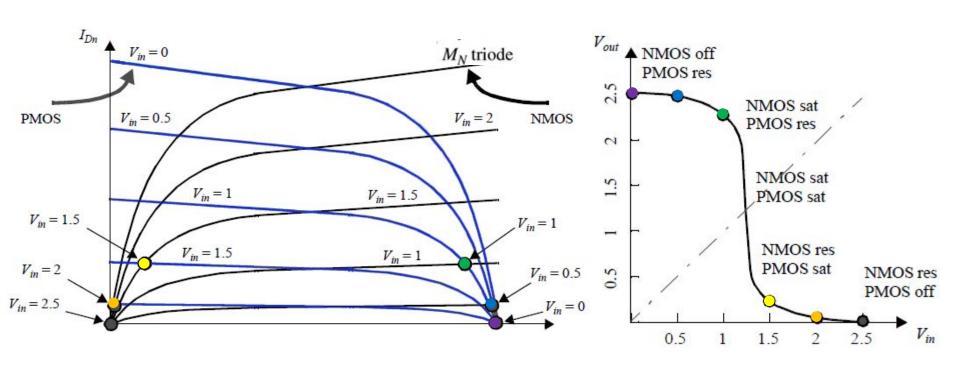
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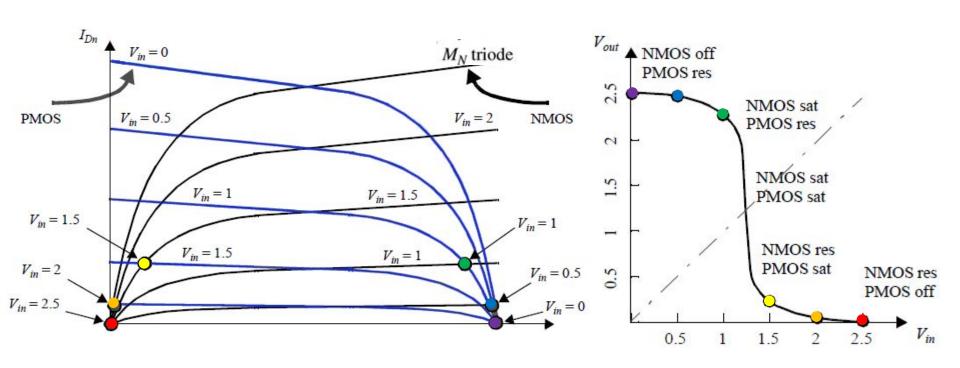
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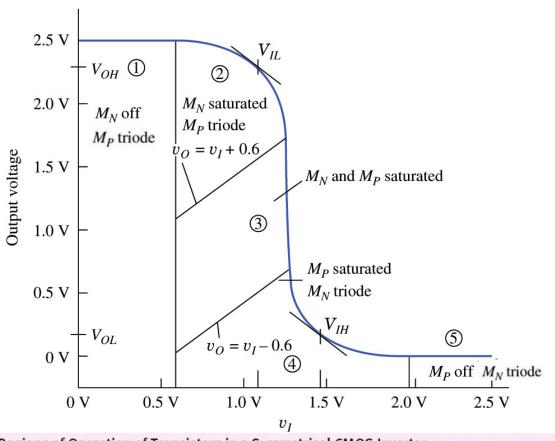
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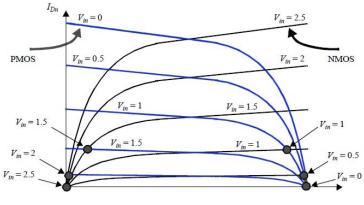
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CMOS Voltage Transfer Characteristics

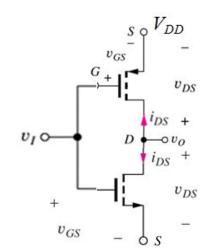


Symmetrical CMOS inverter $(K_p = K_n)$.

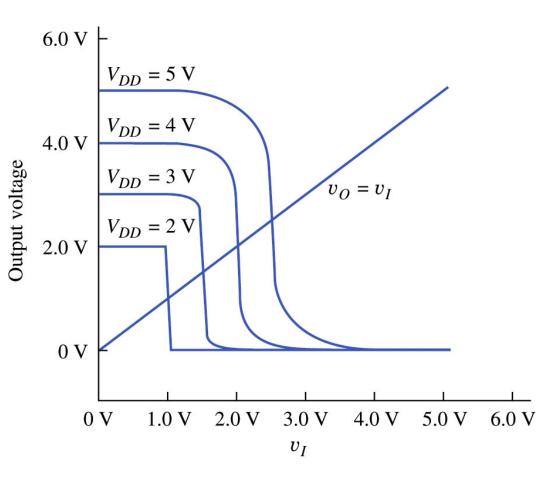


Regions of Operation of	Transistors in a Symmetrica	l CMOS Inverter

Regions of operation of transistors in a symmetrical circos inverter				
REGION	INPUT VOLTAGE v _I	OUTPUT VOLTAGE v _O	NMOS TRANSISTOR	PMOS TRANSISTOR
1	$v_I \leq V_{TN}$	$V_H = V_{DD}$	Cutoff	Triode
2 3	$V_{TN} < v_I \le v_O + V_{TP}$ $v_I \cong V_{DD}/2$	High $V_{DD}/2$	Saturation Saturation	Triode Saturation
4	$v_{I} = v_{DD/2}$ $v_{O} + V_{TN} < v_{I} \le (V_{DD} - V_{TP})$	Low	Triode	Saturation
5	$v_I \ge (V_{DD} - V_{TP})$	$V_L = 0$	Triode	Cutoff

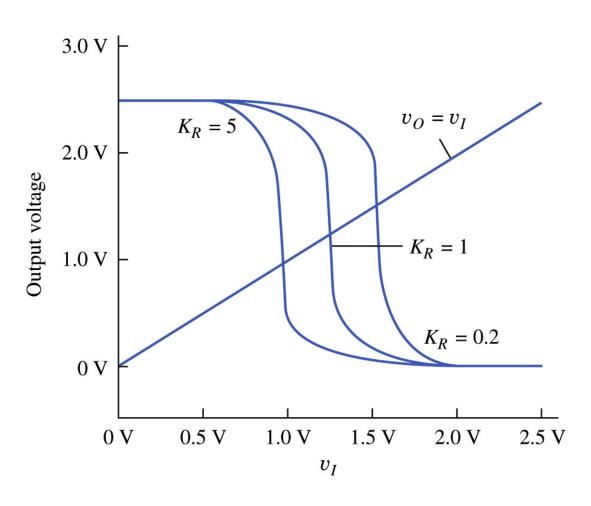


CMOS VTC –Varying V_{DD}



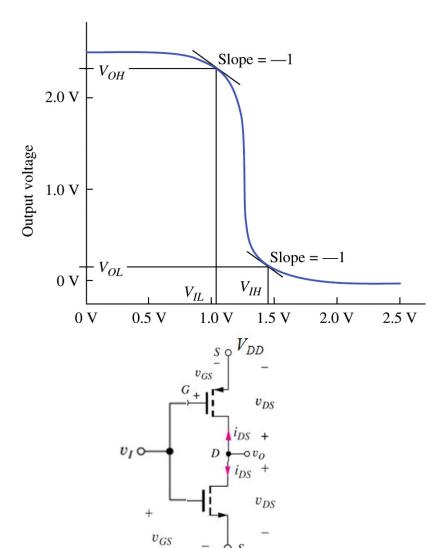
- The simulation results show the changes in VTC of the symmetrical design inverter as V_{DD} is changed
- The transition between V_H and V_L is centered at $V_{DD}/2$ (line $v_O = v_I$)

CMOS VTC –Varying K_N , K_P



- Simulation results show the changes in VTC of the inverter as $K_N/K_P = K_R$ is changed
- For $K_R > 1$ ($K_N > K_P$) the NMOS current drive capability is greater, so the transition region shifts to $v_I < V_{DD}/2$
- For $K_R < 1$ ($K_N < K_P$) the PMOS current drive is greater, and it the transition region shifts toward $v_I > V_{DD}/2$

Noise Margins for the CMOS Inverter



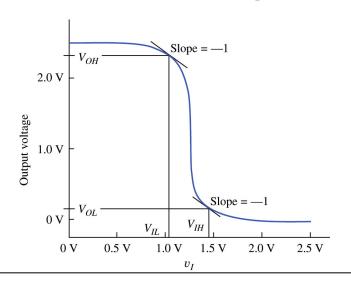
- Noise margins are defined by the points V_{IH} and V_{II} , at which the slope of VTC is -1.
- For v_I near V_{IH} , V_{DS} is large for PMOS (and small for NMOS \square PMOS is saturated, NMOS is in triode. Equating currents and using $K_R = K_N/K_P$), we get

$$K_{R}(2v_{I} - 2V_{TN} - v_{O})(v_{O}) = (v_{I} - V_{DD} - V_{TP})^{2}$$

$$v_{O} = (v_{I} - V_{TN}) \pm \sqrt{(v_{I} - V_{TN})^{2} - \frac{(v_{I} - V_{DD} - V_{TP})^{2}}{K_{R}}}$$

- Taking derivative WRT v_I , and setting it to -1 (quite evolving process) we get $v_I = V_{IH}$ and corresponding $v_o = V_{OL}$
- Repeating the process for For v_I near V_{IL} we get $v_I = V_{IL}$ and corresponding $v_O = V_{OL}$

Noise Margins for the CMOS Inverter



$$NM_L = V_{IL} - V_{OL}$$

$$NM_H = V_{OH} - V_{IH}$$

where
$$K_R = \frac{K_N}{K_P}$$
 and

where
$$K_R = \frac{K_N}{K_P}$$
 and $V_{IH} = \frac{2K_R(V_{DD} - V_{TN} + V_{TP})}{(K_R - 1)\sqrt{1 + 3K_R}} - \frac{(V_{DD} - K_RV_{TN} + V_{TP})}{K_R - 1}$

$$V_{OL} = \frac{(K_R + 1)V_{IH} - V_{DD} - K_RV_{TN} - V_{TP}}{2K_R}$$

$$V_{IL} = \frac{2\sqrt{K_R}(V_{DD} - V_{TN} + V_{TP})}{(K_R - 1)\sqrt{K_R + 3}} - \frac{(V_{DD} - K_RV_{TN} + V_{TP})}{K_R - 1}$$

$$V_{OH} = \frac{(K_R + 1)V_{IL} + V_{DD} - K_RV_{TN} - V_{TP}}{2}$$

• The design of logic gates for CMOC inverter is different from the similar logic design for NMOS inverters that we considered earlier.

WHY?

What is the important difference between NMOS inverter with load transistor and

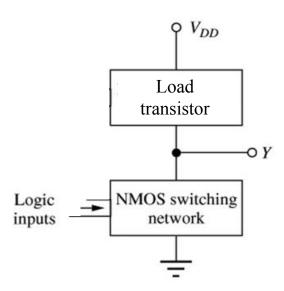
CMOS inverter?

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What is the important difference between NMOS inverter with load transistor and

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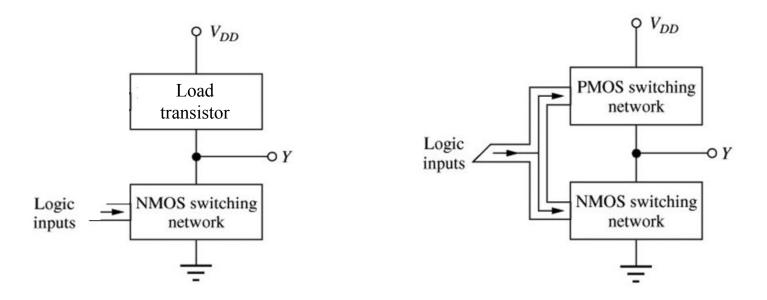


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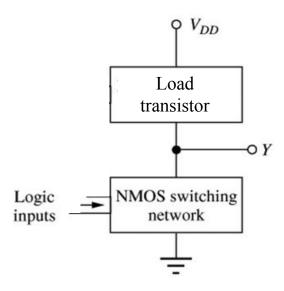
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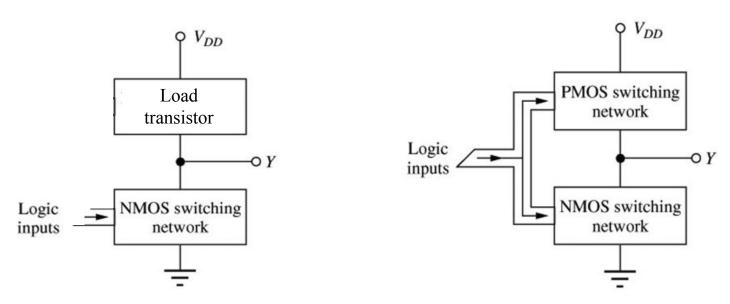


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- For NMOS gates, the logic involved only the switching transistor.



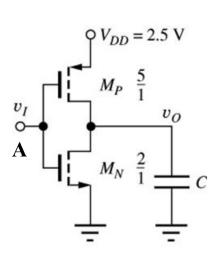
NMOS logic gate structure

- The design of logic gates for CMOC inverter is different from the similar logic design for NMOS inverters that we considered earlier.
- For NMOS gates, the logic involved only the switching transistor.
- For CMOS, both transistors are involved, since the input affects both in symmetrical way.
- Thus, for each logic input variable in CMOS gate there is *one transistor in NMOS* network and *one transistor in PMOS* network.

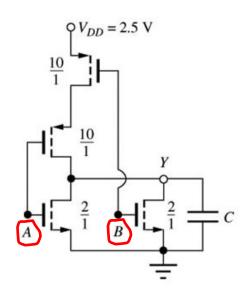


NMOS logic gate structure

CMOS logic gate structure

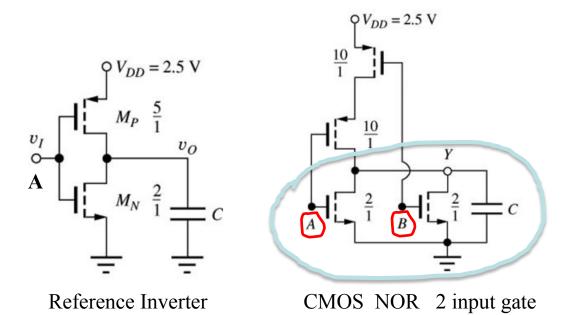


Reference Inverter

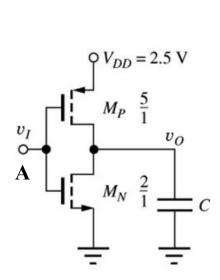


CMOS NOR 2 input gate

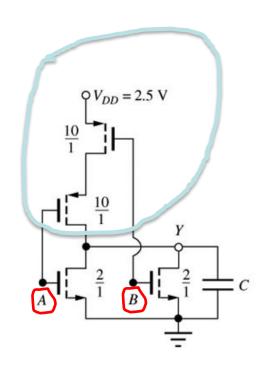
• For the two input NOR gate, the NMOS portion of the gate is identical to the NMOS gate.



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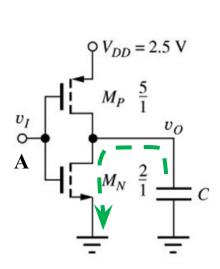


Reference Inverter

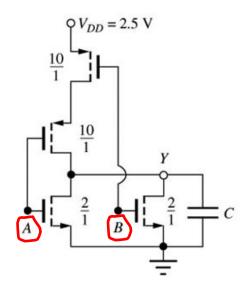


CMOS NOR 2 input gate

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- In the NMOS section, the conducting path exists for A=1 or B=1.

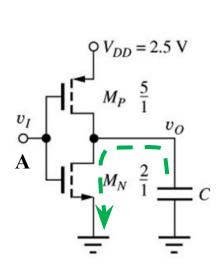




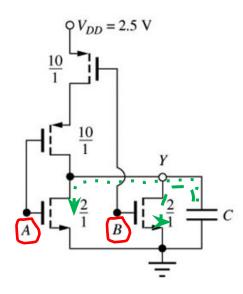


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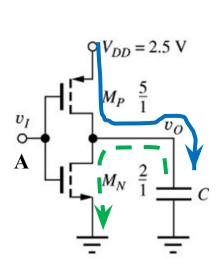


Reference Inverter
A=1 - Y=0



CMOS NOR 2 input gate

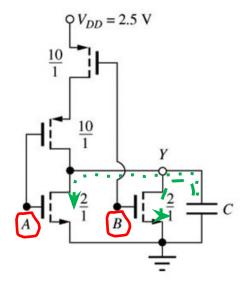
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- In the NMOS section, the conducting path exists for A=1 or B=1.
- In the PMOS section, the conducting path exists only when A=0 and B=0



Reference Inverter

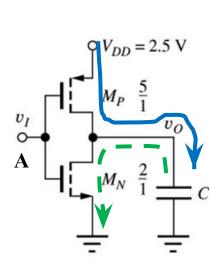
$$A=1 \longrightarrow Y=0$$

$$A=0 \longrightarrow Y=1$$



CMOS NOR 2 input gate

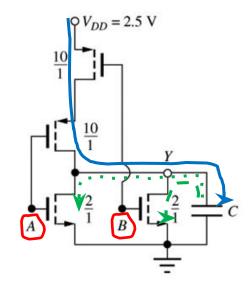
- For the two input NOR gate, the NMOS portion of the gate is identical to the NMOS gate.
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Reference Inverter

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$$A=0 \longrightarrow Y=1$$



CMOS NOR 2 input gate

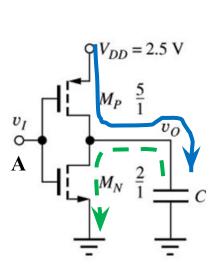
$$A=1 \longrightarrow Y=0$$

$$B=1 \longrightarrow Y=1$$

$$A=0 & B=0 \longrightarrow Y=1$$

CMOS NOR Gate

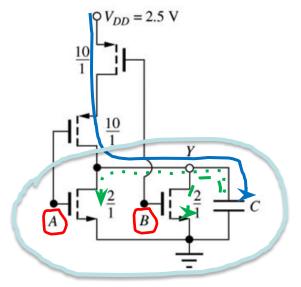
- For the two input NOR gate, the NMOS portion of the gate is identical to the NMOS gate.
- In the CMOS gate, we must ensure that static current path does not exist through the logic gate, and this requires switching also in the PMOS transistor network \Box 2 PMOS transistors.
- In the NMOS section, the conducting path exists for A=1 or B=1.
- In the PMOS section, the conducting path exists only when A=0 and B=0
- Complimentary nature of conducting paths: for NMOS parallel



Reference Inverter

$$A=1 \longrightarrow Y=0$$

$$A=0 \longrightarrow Y=1$$



CMOS NOR 2 input gate

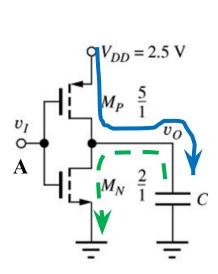
$$A=1 \longrightarrow Y=0$$

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CMOS NOR Gate

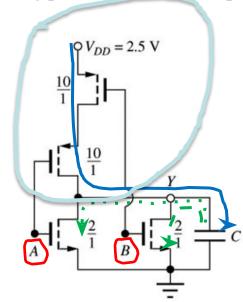
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- Complimentary nature of conducting paths: for **NMOS parallel**, for **PMOS series**



Reference Inverter

$$A=1 \longrightarrow Y=0$$

$$A=0 \longrightarrow Y=1$$



CMOS NOR 2 input gate

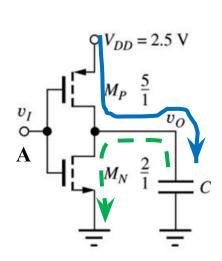
$$A=1 \longrightarrow Y=0$$

$$B=1 \longrightarrow Y=1$$

$$A=0 & B=0 \longrightarrow Y=1$$

CMOS NOR Gate

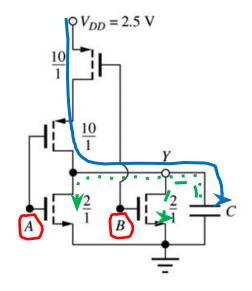
- For the two input NOR gate, the NMOS portion of the gate is identical to the NMOS gate.
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- Complimentary nature of conducting paths: for NMOS parallel, for PMOS series



Reference Inverter

$$A=1 \longrightarrow Y=0$$

$$A=0 \longrightarrow Y=1$$

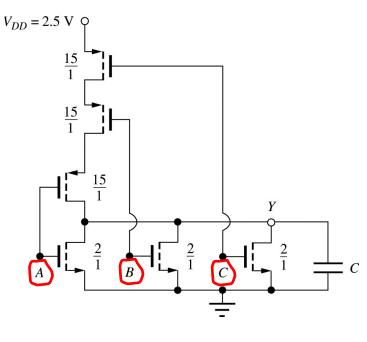


CMOS NOR 2 input gate

$$A=1 \longrightarrow Y=0$$

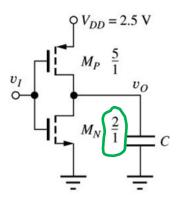
$$B=1 \longrightarrow Y=1$$

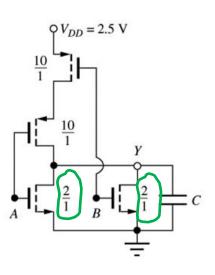
$$A=0 & B=0 \longrightarrow Y=1$$



CMOS NOR 3 input gate

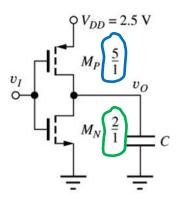
CMOS NOR Gate Transistor Sizing

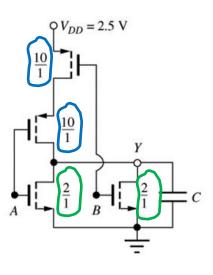




- When sizing the transistors, we attempt to keep the delay times the same as the reference inverter
- To accomplish this, the on-resistance in the PMOS and NMOS branches of the NOR gate must be the same as the reference inverter
- For a two-input NOR gate:
- For the parallel section keep $(W/L)_N$ the same

CMOS NOR Gate Transistor Sizing

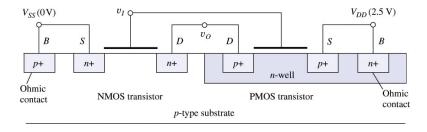




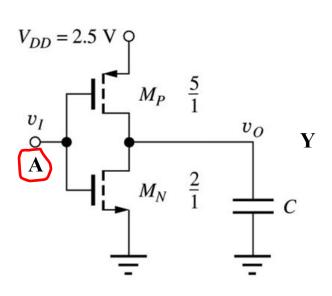
- When sizing the transistors, we attempt to keep the delay times the same as the reference inverter
- To accomplish this, the on-resistance in the PMOS and NMOS branches of the NOR gate must be the same as the reference inverter
- For a two-input NOR gate:
- For the parallel section keep $(W/L)_N$ the same
- For the series section $(W/L)_p$ must be made twice as large.

CMOS NOR Gate Body Effect

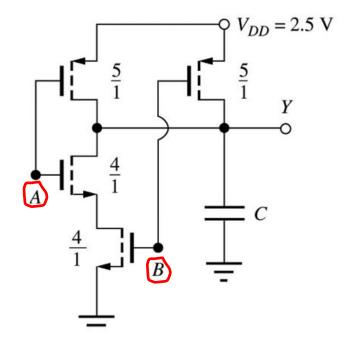
• Due to design, the bottom PMOS body contact is not connected to its source, its threshold voltage changes as V_{SB} changes during switching



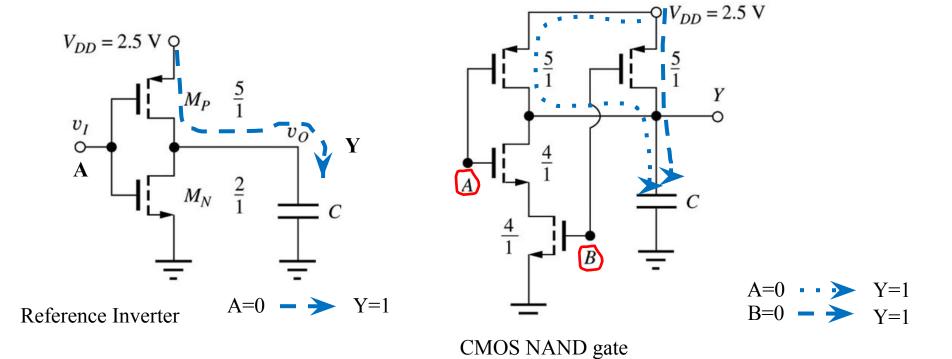
- Once $v_O = V_H$ is reached, the bottom PMOS is not affected by body effect (because all the line from V_{DD} to v_O is at V_H , thus the total on-resistance of the PMOS branch is the same
- However, the rise time is slowed down slightly due to $|V_{TP}|$ being a function of time

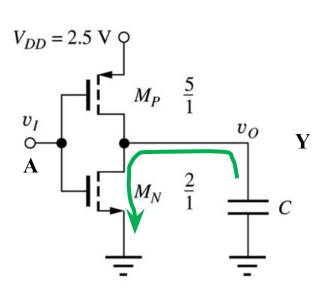


Reference Inverter



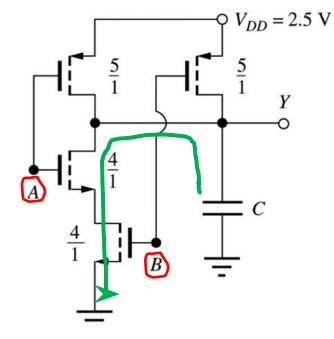
CMOS NAND gate





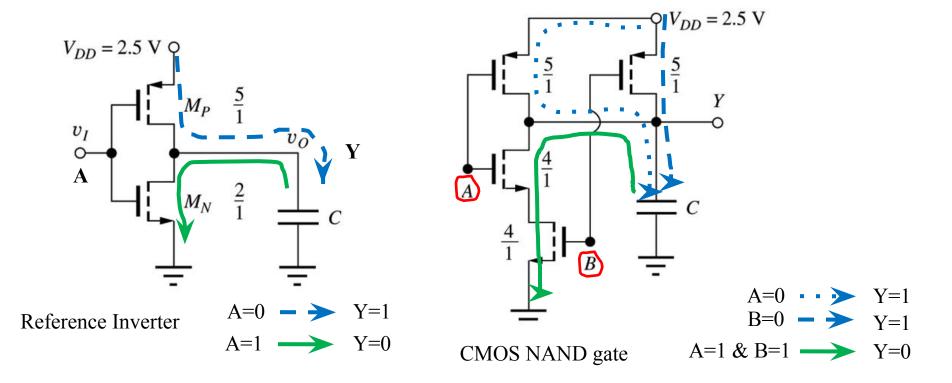
Reference Inverter

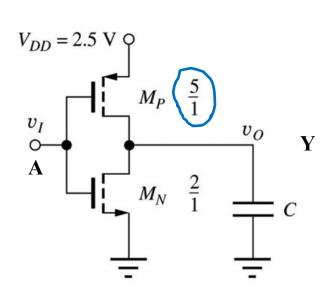
$$A=1 \longrightarrow Y=0$$



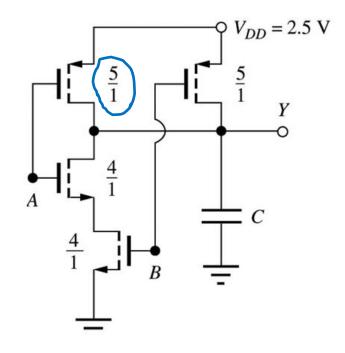
CMOS NAND gate

$$A=1 \& B=1 \longrightarrow Y=0$$



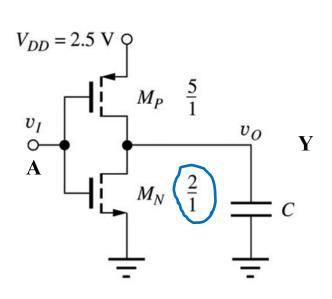


Reference Inverter

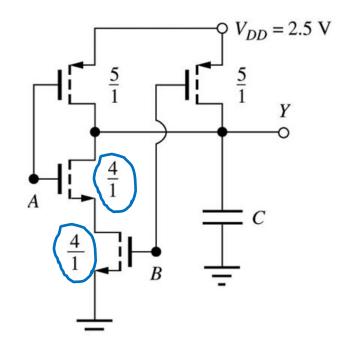


CMOS NAND gate

- The same rules apply for sizing the NAND gate devices as for the NOR gate, except now the NMOS transistors are in series
- (W/L)_p will be the same size of that of the reference inverter



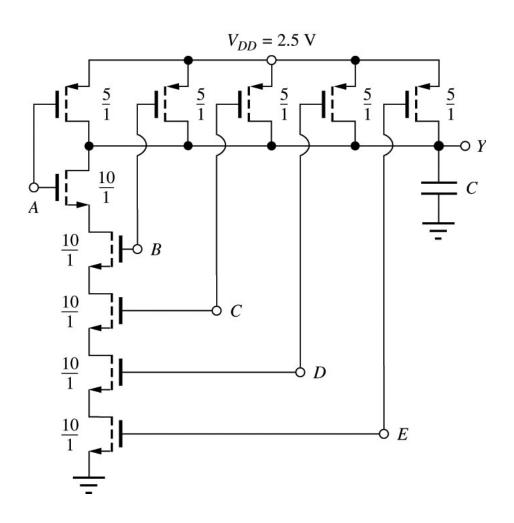
Reference Inverter



CMOS NAND gate

- The same rules apply for sizing the NAND gate devices as for the NOR gate, except now the NMOS transistors are in series
- (W/L)_p will be the same size of that of the reference inverter
- (W/L)_N will be twice the size of that of the reference inverter

Multi-Input CMOS NAND Gates



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- The process consists of **two** steps:
 - design the **NMOS** circuit structure and the corresponding graph of the logic function
 - build the **graph** for the complementary logic function and then design the complementary logic PMOS circuit **OR invert** the original function using the **DeMorgan's law** and design the corresponding network.

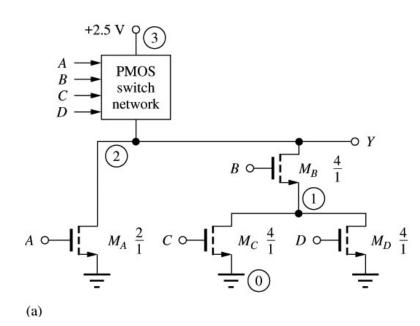
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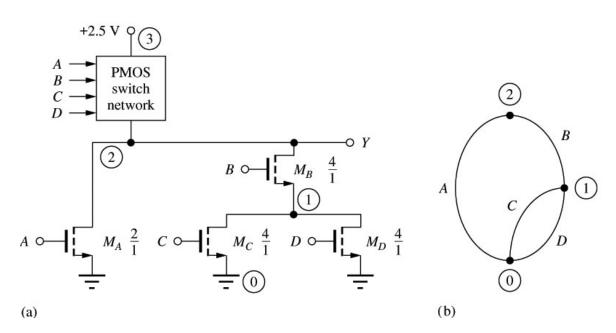
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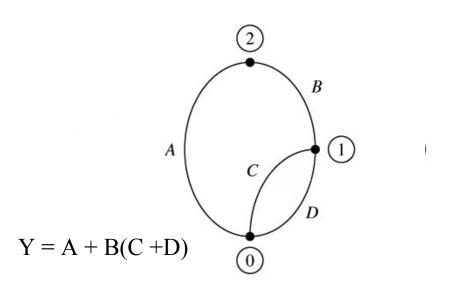


NJIT ECE 271 Dr, Serhiy Levkov

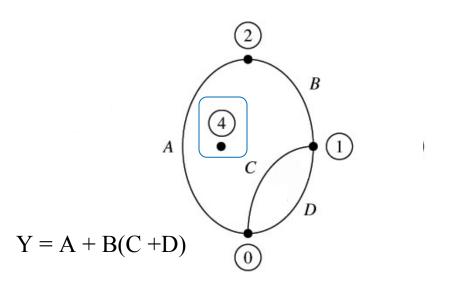
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- Then the corresponding graph can be drawn: each arc represent an NMOS transistor and each node correspond to the circuit node.



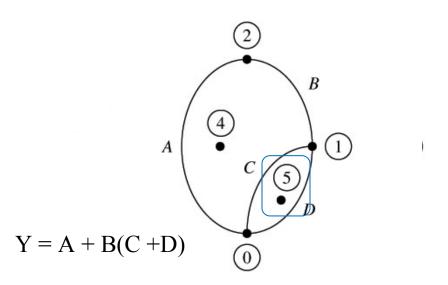
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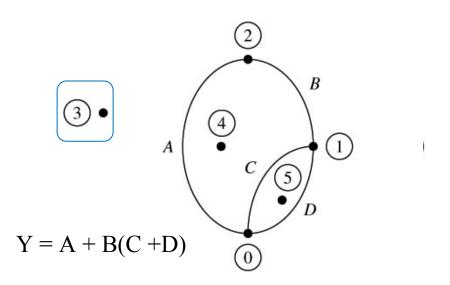
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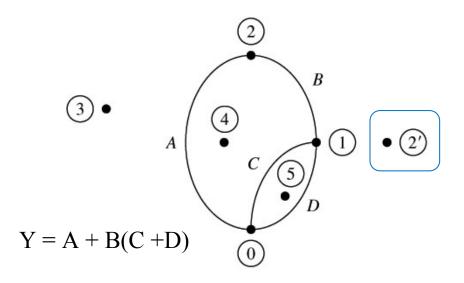
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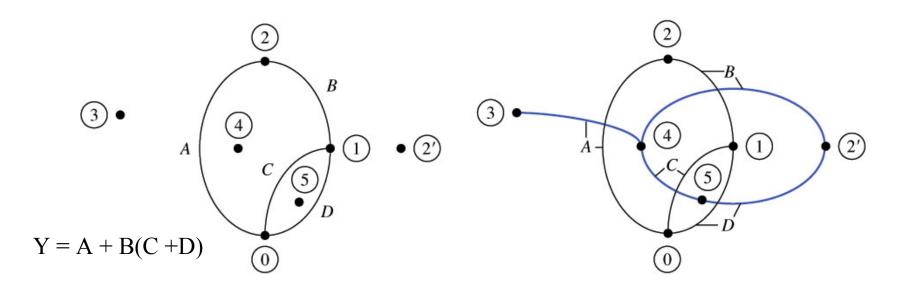
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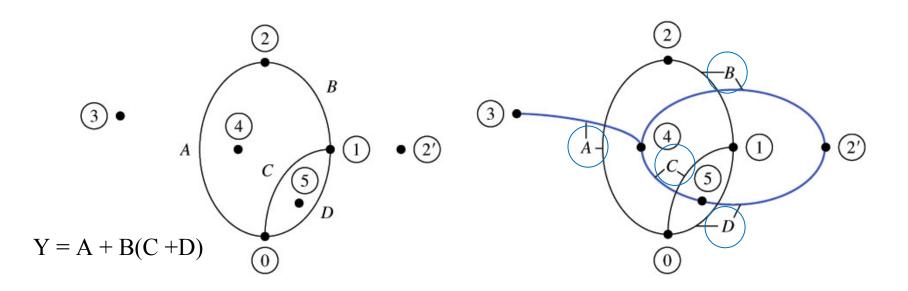
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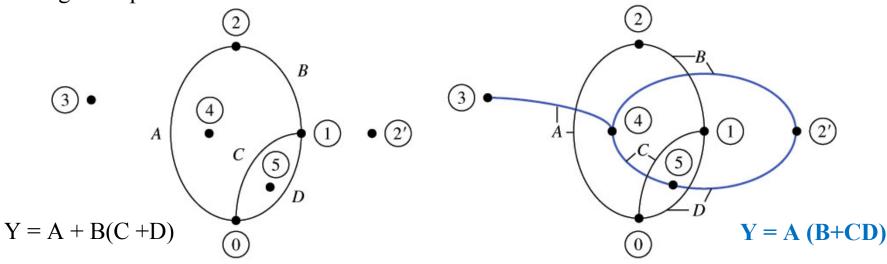
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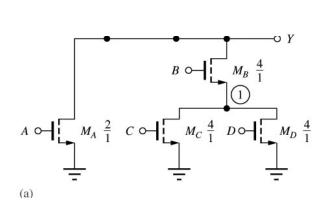
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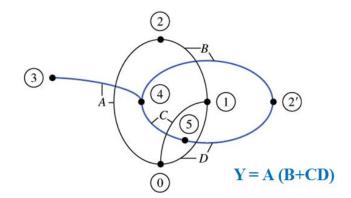
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- Connect all of the nodes by drawing the arcs (PMOS transistors) that cut the arcs of the original NMOS graph and label them as the arcs they intersect.
- This construction results in the minimum PMOS logic network that has one transistor per logical input.

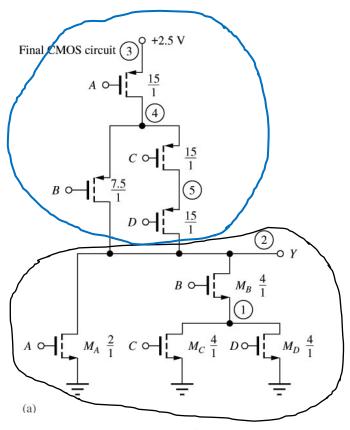


 From the PMOS graph, the PMOS network can now be drawn for the final CMOS logic gate



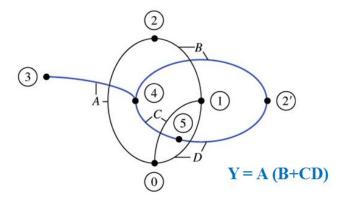
Final CMOS circuit

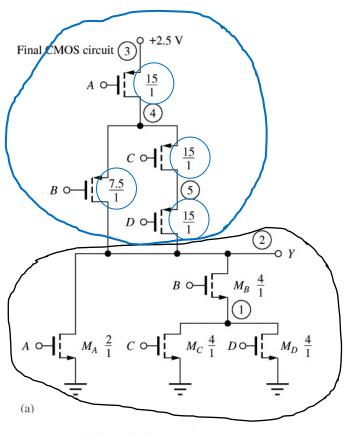




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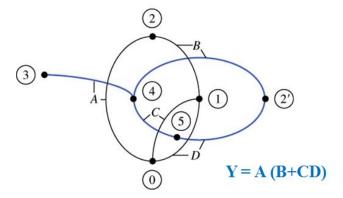
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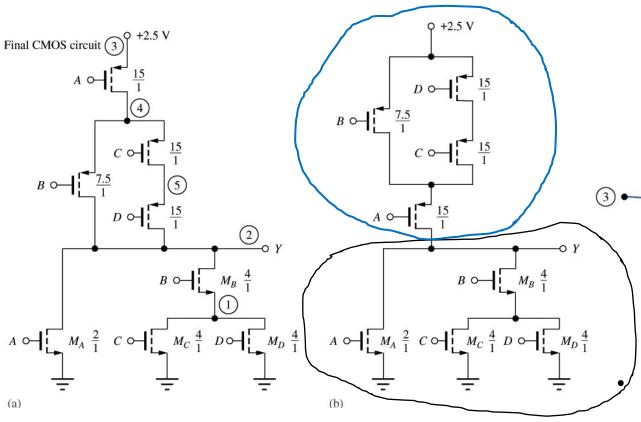
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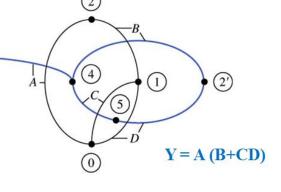


For sizing we once again consider the longest PMOS path, where
 (W/L)_{p,ref} = 5/1.

The alternative designs for PMOS circuit



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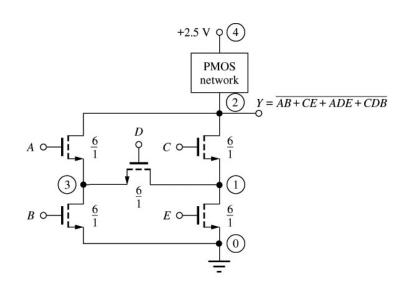
Final CMOS circuit

Complex CMOS Gate with a Bridging Transistor - Design Example

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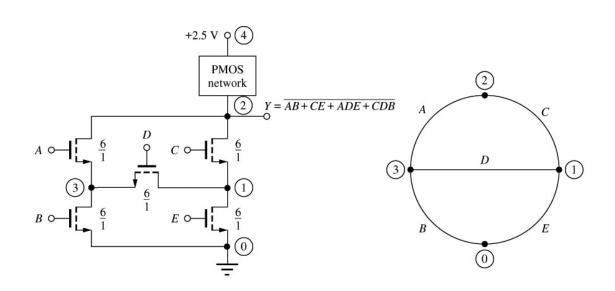
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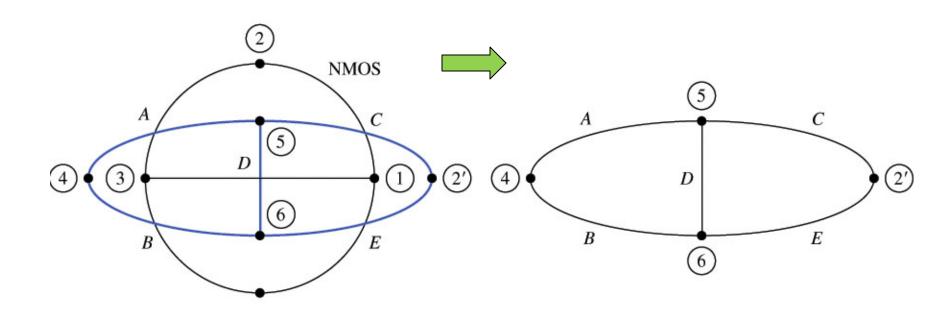
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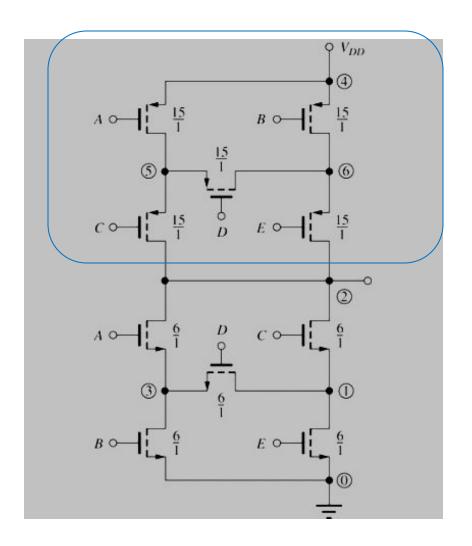


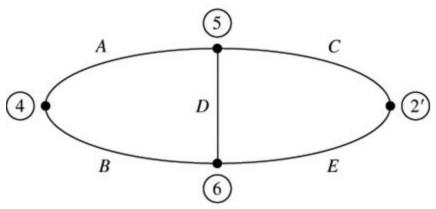
Complex CMOS Gate with a Bridging Transistor - Design Example

• By using the same technique as before, the PMOS graph can now be drawn



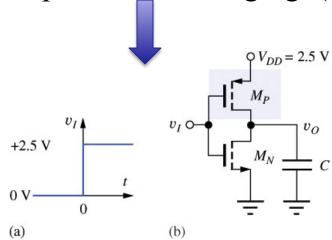
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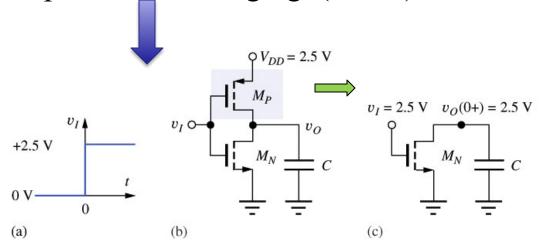


• By using the PMOS graph, the PMOS network can now be realized as shown (considering the longest path for sizing)

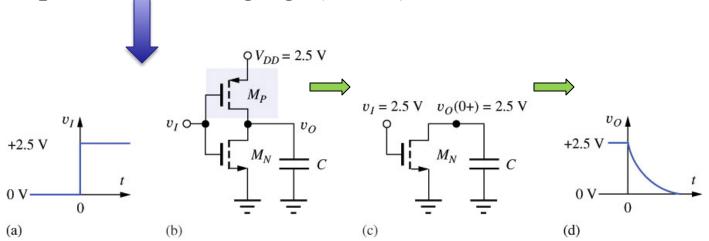
• The propagation delays are created by the process of capacitive discharging $(L \square H)$



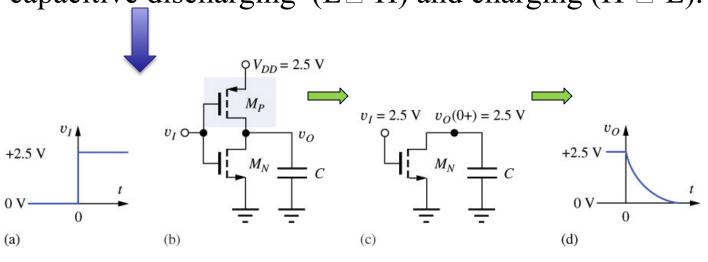
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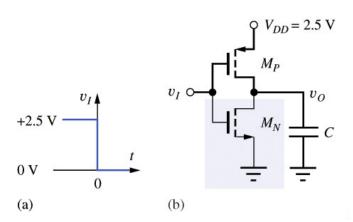


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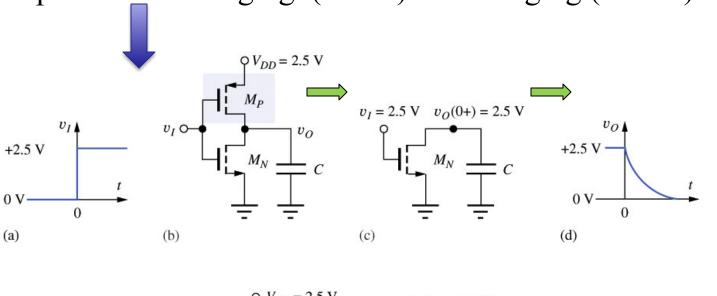


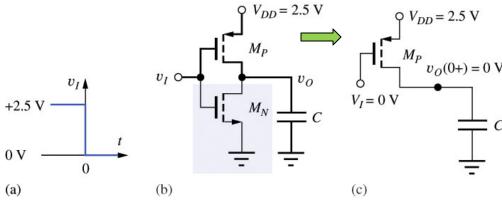
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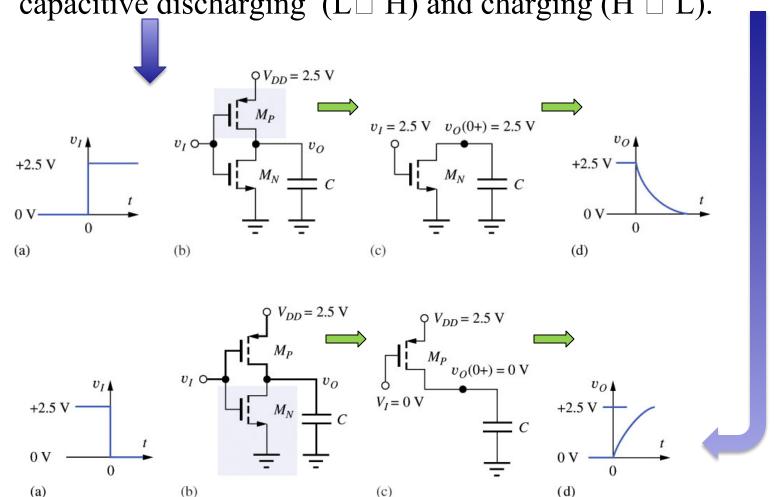


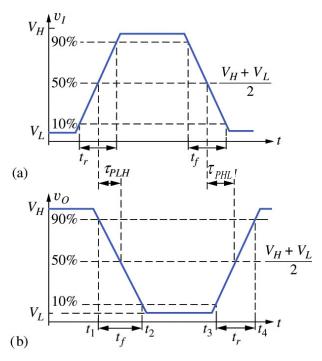
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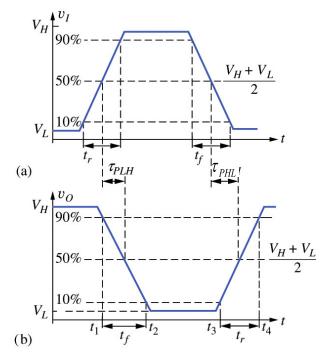


To estimate the propagation delay, we use the approximate expression, which employs equivalent resistance of a transistor in the ON state, that was developed for the NMOS.

$$\begin{split} \tau_{PHL} &= 1.2 R_{onN} C & \tau_{LH} &= 1.2 R_{onP} C \\ R_{onN} &= \frac{1}{K_n \left(V_H - V_{TN}\right)} & R_{onP} &= \frac{1}{K_p \left(V_H + V_{TP}\right)} \end{split}$$

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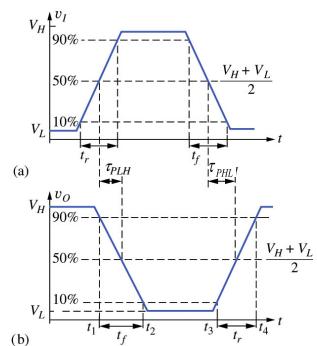


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• If it is assumed the inverter is "symmetrical" with $(W/L)_p = 2.5(W/L)_N$, then $\tau_{PLH} = \tau_{PHL}$ and

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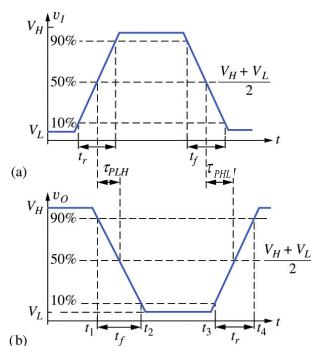
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$$\tau_{p} = \frac{\tau_{PHL} + \tau_{PLH}}{2} = \tau_{PHL} = 1.2R_{onN}C$$

The rise and fall times are given by the following approximate expressions:

$$t_f = 3\tau_{PHL}, \ t_r = 3\tau_{PLH}$$



• Design a reference inverter to achieve a delay of 250ps with a 0.2pF load given the following information:

$$V_{DD} = 3.3V, C = 0.2 pF$$

 $\tau_p = 250 ps, V_{TN} = -V_{TP} = 0.75V$

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• Assuming the inverter is symmetrical and using the typical values (Table 7.1):

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$$R_{onN} = \frac{1}{K_n \left(\frac{W}{L}\right)_N \left(V_H - V_{TN}\right)}$$

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$$R_{onN} = \frac{1}{K_n \left(\frac{W}{L}\right)_N \left(V_H - V_{TN}\right)}$$
we get

$$\left(\frac{W}{L}\right)_{n} = \frac{1}{K_{n}' R_{onN} \left(V_{DD} - V_{TN}\right)} = \frac{3.77}{1}$$

$$\left(\frac{W}{L}\right)_{p} = \frac{K'_{n}}{K'_{p}} \left(\frac{W}{L}\right)_{n} = 2.5 \left(\frac{W}{L}\right)_{n} = \frac{9.43}{1}$$

Using similarity btw current expressions for N and P

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- Thus, scaling can be used to set new W/L for a new load capacitance relative to reference gate simulation with a reference load capacitance:

$$\tau_{P}^{'} = \frac{(W/L)_{ref}}{(W/L)'} \times \left(\frac{C_{L}^{'}}{C_{Lref}}\right) \times \tau_{Pref} \implies \left(\frac{W}{L}\right)' = \left(\frac{W}{L}\right)_{ref} \times \left(\frac{\tau_{Pref}}{\tau_{P}^{'}}\right) \times \left(\frac{C_{L}^{'}}{C_{Lref}}\right)$$

Scaling allows us to calculate a new geometry (W/L)' in terms of a target load and delay.

Performance Scaling Example

- Consider a reference inverter with a delay of 3.16 ns and W/L = 2/1.
- What is the delay if an inverter has a W/L 4 time larger than the transistors of the reference inverter and twice the load capacitance?

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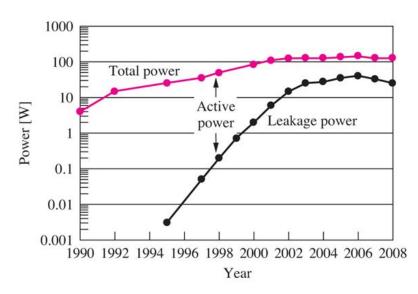
$$\tau_P = \frac{(2/1)}{(8/1)!} \times \left(\frac{2pF'}{1pF}\right) \times 3.16 \text{ ns} = 1.58 \text{ ns}$$

Scaling allows us to calculate $new\ geometry\ (W/L)'$ or delay relative to a reference design.

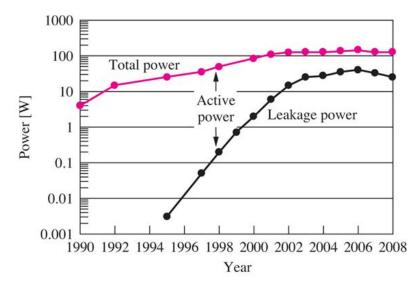
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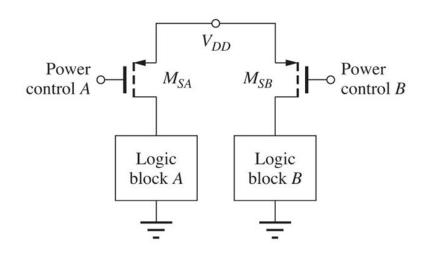
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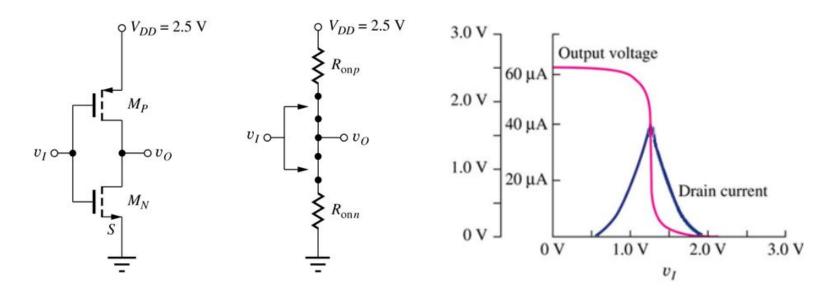
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- Special methods are developed to reduce the static power, like adding large PMOS to control the power to the certain logic blocks when they are not needed, which can be done either using hardware or software control.





Dynamic Power Dissipation

- There are two components that contributes to dynamic power dissipation:
- As we found earlier, the capacitive load charging/discharging at a frequency f is responsible for power dissipation $P_D = CV^2_{DD} f$
- The second mechanism is created by drain current through both transistors during the short period of switching when both transistors are ON and in saturation region.
- That current exists when $V_{TN} < v_I < (V_{DD} |V_{TP}|)$ and reaches max when $v_I = v_O = V_{DD}/2$.

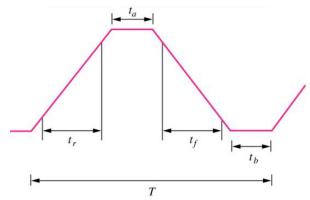


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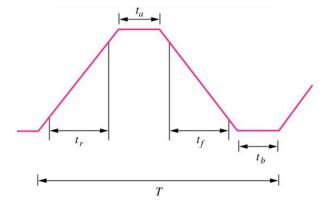
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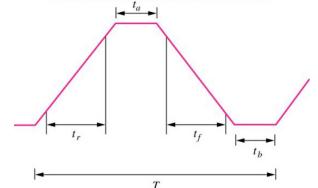
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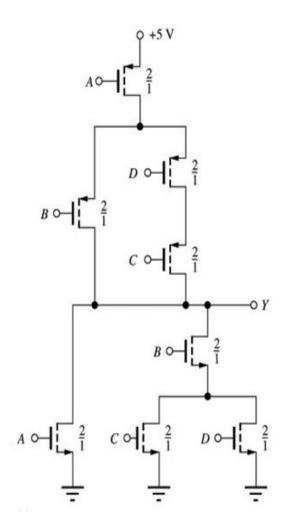
• This shows importance of reducing the power supply voltage, since PDP is reduced proportionally to square of V_{DD} .

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- If minimum feature sized are used for both devices, then the τ_{PLH} will be increased compared to the symmetrical reference inverter

